**DW OR N PACKAGE** 

(TOP VIEW)

PGND [

SER IN **1** 3

DRAIN0 [] 4

DRAIN1 **1** 5

DRAIN2 6

DRAIN3 7

SRCLR II 8

GΠ

9

V<sub>CC</sub> 2

20 PGND

19 LGND

18 SER OUT

17 DRAIN7

16 DRAIN6

15 DRAIN5

14 DRAIN4

13 SRCK

12 ∏ RCK

- Low r<sub>DS(on)</sub> . . . 1.3 Ω Typical
- Avalanche Energy . . . 75 mJ
- Eight Power DMOS Transistor Outputs of 250-mA Continuous Current
- 1.5-A Pulsed Current Per Output
- Output Clamp Voltage at 45 V
- Devices Are Cascadable
- Low Power Consumption

## description

The TPIC6595 is a monolithic, high-voltage, highcurrent power 8-bit shift register designed for use in systems that require relatively high load power. The device contains a built-in voltage clamp on the outputs for inductive transient protection. Power driver applications include relays, solenoids, and other medium-current or high-voltage loads.

This device contains an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. Data transfers through both the shift and storage registers on the rising edge of the shift-register clock (SRCK) and the register clock (RCK) respectively. The storage register transfers data to the output buffer when shift-register clear (SRCLR) is high. When SRCLR is low, the input shift register is cleared. When output enable (G) is held high, all data in the output buffers is held low and all drain outputs are off. When G is held low, data from the storage register is transparent to the output buffers. The serial output (SER OUT) allows for cascading of the data from the shift register to additional devices.

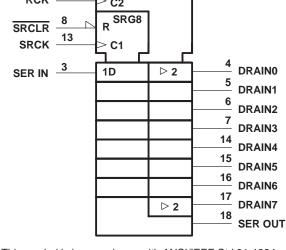
Outputs are low-side, open-drain DMOS transistors with output ratings of 45 V and 250-mA

PGND [ 10 11 PGND

logic symbol†

G 9 EN3
RCK 12 C2
SRCLR 8 SRG8
SRCK 13 C1

SER IN 3 1D D 2 4 DRAIN



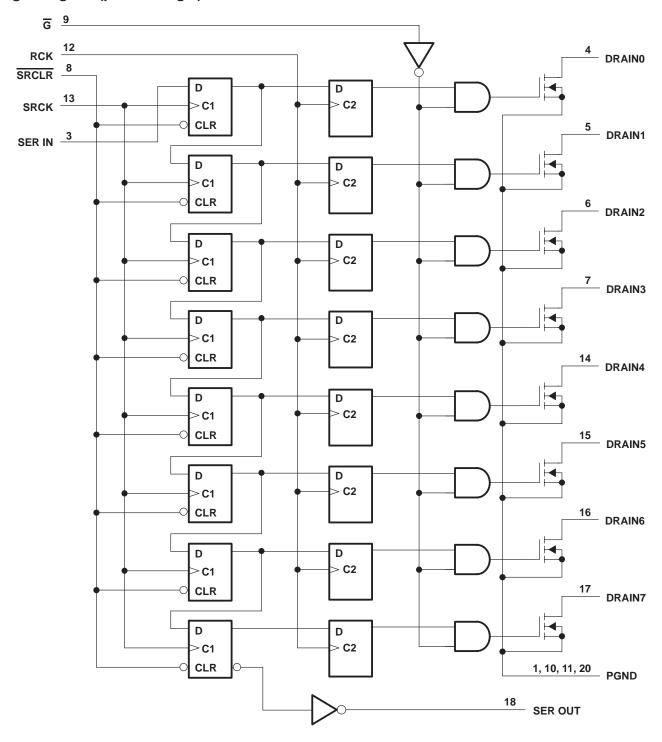
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

continuous sink current capability. When data in the output buffers is low, the DMOS-transistor outputs are off. When data is high, the DMOS-transistor outputs have sink current capability.

Separate power and logic level ground pins are provided to facilitate maximum system flexibility. Pins 1, 10, 11, and 20 are internally connected, and each pin must be externally connected to the power system ground in order to minimize parasitic inductance. A single-point connection between pin 19, logic ground (LGND), and pins 1, 10, 11, and 20, power grounds (PGND), must be externally made in a manner that reduces crosstalk between the logic and load circuits.

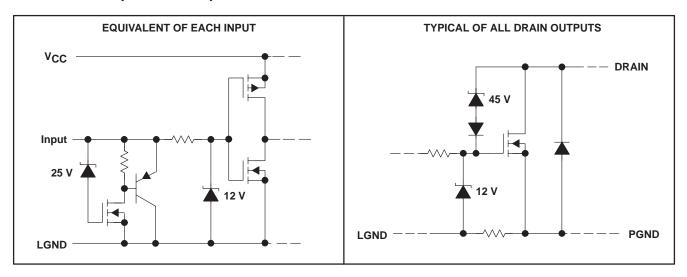
The TPIC6595 is characterized for operation over the operating case temperature range of -40°C to 125°C.

## logic diagram (positive logic)





## schematic of inputs and outputs



# absolute maximum ratings over recommended operating case temperature range (unless otherwise noted) $^{\dagger}$

Logic supply voltage, V <sub>CC</sub> (see Note NO TAG)	
Power DMOS drain-to-source voltage, V <sub>DS</sub> (see Note NO TAG)	
Continuous source-drain diode anode current	1 A
Pulsed source-drain diode anode current	2 A
Pulsed drain current, each output, all outputs on, I <sub>Dn.</sub> T <sub>A</sub> = 25°C (see Note NC	TAG) 750 mA
Continuous drain current, each output, all outputs on, I <sub>Dn.</sub> T <sub>A</sub> = 25°C	
Peak drain current single output, I <sub>DM</sub> , T <sub>A</sub> = 25°C (see Note NO TAG)	2 A
Single-pulse avalanche energy, E <sub>AS</sub> (see NO TAG)	
Avalanche current, I <sub>AS</sub> (see Note NO TAG)	1 A
Continuous total power dissipation	
Operating virtual junction temperature range, T <sub>J</sub>	–40°C to 150°C
Storage temperature range, T <sub>stq</sub>	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values are with respect to LGND and PGND.
  - 2. Each power DMOS source is internally connected to PGND.
  - 3. Pulse duration  $\leq$  100  $\mu$ s, duty cycle  $\leq$  2 %
  - 4. DRAIN supply voltage = 15 V, starting junction temperature (TJS) = 25°C, L = 100 mH, IAS = 1 A (see NO TAG).

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 125°C POWER RATING
DW	1125 mW	9.0 mW/°C	225 mW
N	1150 mW	9.2 mW/°C	230 mW



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# recommended operating conditions over recommended operating temperature range (unless otherwise noted)

	MIN	MAX	UNIT
Logic supply voltage, V <sub>CC</sub>	4.5	5.5	V
High-level input voltage, V <sub>IH</sub>	0.85 V <sub>CC</sub>		V
Low-level input voltage, V <sub>IL</sub>		0.15 V <sub>CC</sub>	V
Pulsed drain output current, T <sub>C</sub> = 25°C, V <sub>CC</sub> = 5 V (see Notes 3 and 5)	-1.8	1.5	Α
Setup time, SER IN high before SRCK↑, t <sub>SU</sub> (see NO TAG)	10		ns
Hold time, SER IN high after SRCK↑, t <sub>h</sub> (see NO TAG)	10		ns
Pulse duration, t <sub>W</sub> (see NO TAG)	20		ns
Operating case temperature, T <sub>C</sub>	-40	125	°C

## electrical characteristics, $V_{CC}$ = 5 V, $T_{C}$ = 25°C (unless otherwise noted)

	PARAMETER		TEST CONDI	TIONS	MIN	TYP	MAX	UNIT
V <sub>(BR)</sub> DSX	Drain-source breakdown voltage	$I_D = 1 \text{ mA}$			45			V
$V_{SD}$	Source-drain diode forward voltage	$I_F = 250 \text{ mA},$	See Note 3			0.85	1	V
Va	High-level output voltage, SER OUT	$I_{OH} = -20 \text{ mA}$	$V_{CC} = 4.5 \text{ V}$		4.4	4.49		V
VOH		$I_{OH} = -4 \text{ mA},  V_{CC} = 4.5 \text{ V}$			4.1	4.3		v
Voi	Low-level output voltage, SER	I <sub>OH</sub> = 20 mA, V <sub>CC</sub> = 4.5 V				0.002	0.1	V
VOL	OUT	$I_{OH} = 4 \text{ mA},$	$V_{CC} = 4.5 V$			0.2	0.4	V
V <sub>(hys)</sub>	Input hysteresis	V <sub>DS</sub> = 15 V				1.3		V
lн	High-level input current	$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$				1	μΑ
I <sub>I</sub> L	Low-level input current	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 0				-1	μΑ
ICCL	Logic supply current	$I_{O} = 0$ ,	All inputs low			15	100	μΑ
ICC(FRQ)	Logic supply current frequency	f <sub>SRCK</sub> = 5 MHz, I <sub>O</sub> = 0, C <sub>L</sub> = 30 pF, See Figures 1, 2, and 6			0.6	5	mA	
I <sub>N</sub>	Nominal current	$V_{DS(on)} = 0.5$ $I_{N} = I_{D}$		See Notes 5, 6, and 7		250		mA
lnov	Off-state drain current	V <sub>DS</sub> = 40 V			0.05	1		
DSX	On-state drain current	$V_{DS} = 40 \text{ V},$	T <sub>C</sub> = 125°C			0.15	5	μΑ
		$I_D = 250 \text{ mA},$	V <sub>CC</sub> = 4.5 V			1.3	2	
r <sub>DS(on)</sub>	Static drain-source on-state resistance	$I_D = 250 \text{ mA},$ $V_{CC} = 4.5 \text{ V}$	$T_{C} = 125^{\circ}C,$	See Notes 5 and 6 and Figures 9 and 10		2	3.2	Ω
		$I_D = 500 \text{ mA},$	V <sub>CC</sub> = 4.5 V	NO TAG		1.3	2	

## switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_{C} = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPLH	Propagation delay time, low-to-high-level output from $\overline{G}$			650		ns
tPHL	Propagation delay time, high-to-low-level output from $\overline{G}$	$C_L = 30 \text{ pF}, \qquad I_D = 250 \text{ mA},$		150		ns
t <sub>r</sub>	Rise time, drain output	See Figures 1 and 2		750		ns
t <sub>f</sub>	Fall time, drain output			425		ns
ta	Reverse-recovery-current rise time	I <sub>F</sub> = 250 mA, di/dt = 20 A/μs,		100		20
t <sub>rr</sub>	Reverse-recovery time	See Notes 5 and 6 and Figure 3		300		ns

NOTES: 3. Pulse duration  $\leq 100 \,\mu\text{s}$ , duty cycle  $\leq 2\%$ 

- 5. Technique should limit  $T_J T_C$  to 10°C maximum.
- 6. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.
- Nominal current is defined for a consistent comparison between devices from different sources. It is the current that produces a voltage drop of 0.5 V at T<sub>C</sub> = 85°C.



#### thermal resistance

PARAMETER		TEST CONDITIONS	MIN MAX	UNIT
R <sub>θJA</sub> Thermal resistance, junction-to-ambient	DW package	All 8 outputs with equal power	11	¹ °C/W
	N package	All 6 outputs with equal power	10	

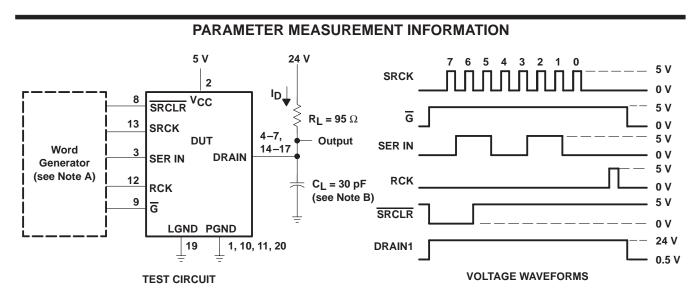


Figure 1. Resistive Load Operation

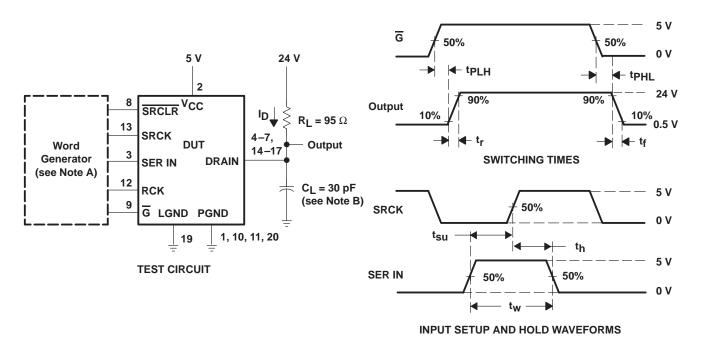


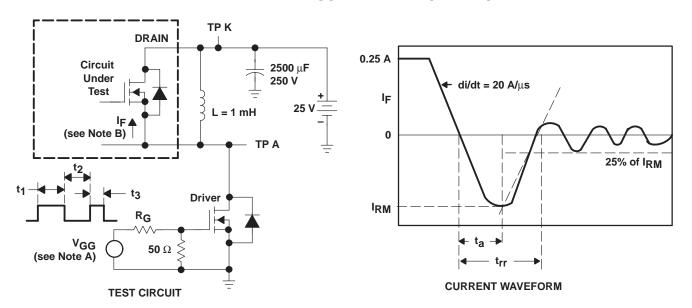
Figure 2. Test Circuit, Switching Times, and Voltage Waveforms

NOTES: A. Outputs DRAIN 1, 2, 5, and 6 low (PGND), all other DRAIN outputs are at 24 V. The word generator has the following characteristics:  $t_{\Gamma} \le 10$  ns,  $t_{W} = 300$  ns, pulsed repetition rate (PRR) = 5 kHz,  $Z_{O} = 50 \Omega$ .

B. C<sub>I</sub> includes probe and jig capacitance.

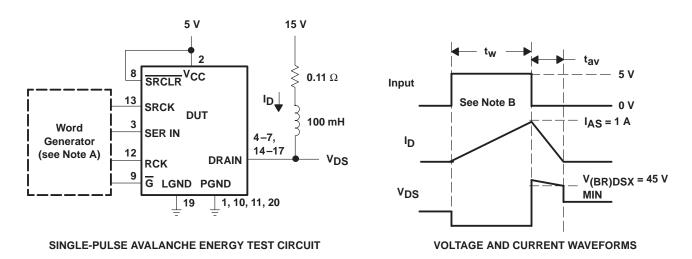


### PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The VGG amplitude and RG are adjusted for di/dt = 20 A/ $\mu$ s. A VGG double-pulse train is used to set IF = 0.25 A, where  $t_1$  = 10  $\mu$ s,  $t_2$  = 7  $\mu$ s, and  $t_3$  = 3  $\mu$ s.
  - B. The DRAIN terminal under test is connected to the TP K test point. All other terminals are connected together and connected to the TP A test point.

Figure 3. Reverse-Recovery-Current Test Circuit and Waveforms of Source-Drain Diode



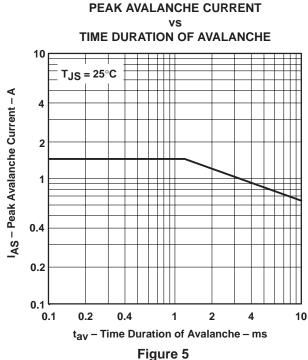
- NOTES: A. The word generator has the following characteristics:  $t_{\Gamma} \le$  10 ns,  $t_{f} \le$  10 ns,  $Z_{O} = 50 \ \Omega$ .
  - B. Input pulse duration,  $t_W$ , is increased until peak current  $I_{AS} = 1$  A. Energy test level is defined as  $E_{AS} = I_{AS} \times V_{(BR)DSX} \times t_{aV}/2 = 75$  mJ, where  $t_{aV}$  = avalanche time.

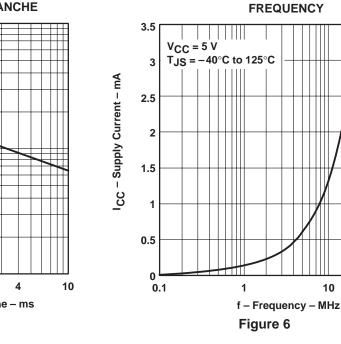
Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms

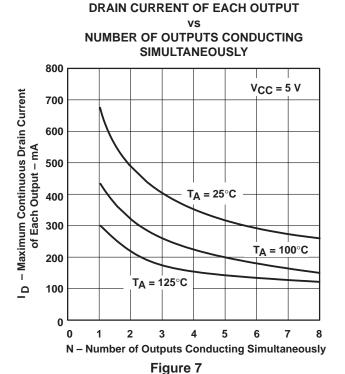


SUPPLY CURRENT vs

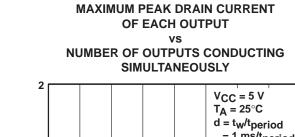
### TYPICAL CHARACTERISTICS

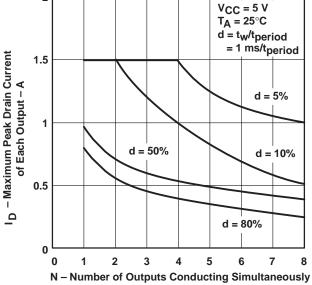






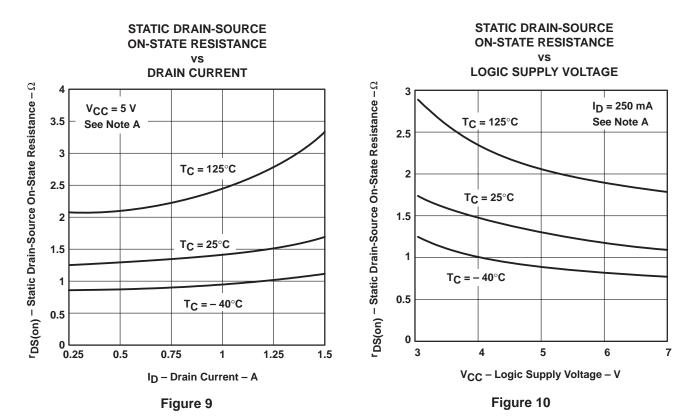
**MAXIMUM CONTINUOUS** 

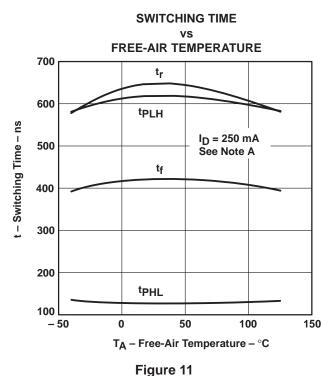




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## **TYPICAL CHARACTERISTICS**





NOTE A: Technique should limit  $T_J - T_C$  to 10°C maximum.



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